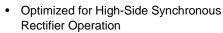


8001H-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^a	Q _g (Typ.)		
30	0.008 at V _{GS} = 10 V	13	6.1 nC		
	0.011 at V _{GS} = 4.5 V	11	0.1110		



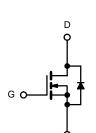




- 100 % R_g Tested
- 100 % UIS Tested



- Notebook CPU Core
 - High-Side Switch



N-Channel MOSFET

S _S G
DFN 3x3

ABSOLUTE MAXIMUM RATINGS T	_A = 25 °C, unles	s otherwise note	d		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	30	V		
Gate-Source Voltage		V_{GS}	± 20		
	T _C = 25 °C		13		
Continuous Drain Current (T = 150 °C)	T _C = 70 °C		10		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	9 ^{b, c}		
	T _A = 70 °C		7 ^{b, c}	^	
Pulsed Drain Current		I _{DM}	45	A	
Cantinuary Course Brain Binds Courset	T _C = 25 °C	1	3.7		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.0 ^{b, c}		
Single Pulse Avalanche Current	1 0.4 ml l	I _{AS}	20		
Avalanche Energy	L = 0.1 mH		21	mJ	
	T _C = 25 °C		4.1		
Maximum Davies Dissination	T _C = 70 °C	D	2.5	10/	
Maximum Power Dissipation	T _A = 25 °C	P _D	2.2 ^{b, c}	w	
	T _A = 70 °C		1.3 ^{b, c}		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	39	55	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	25	29	C/VV	

Notes:

- a. Base on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 85 °C/W.



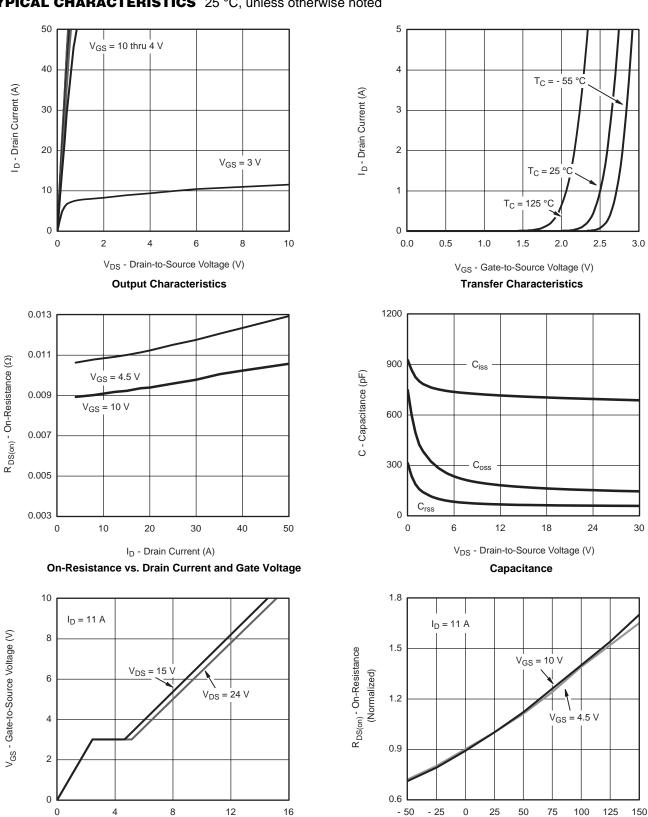
SPECIFICATIONS $T_J = 25$ °C, unless otherwise noted Parameter Symbol Test Conditions Min. Typ. Maximum						Unit	
Static				.,,,,	1		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	/T _J I _D = 250 µA		26		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 6			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.8		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V			1	μΑ	
	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α	
Drain-Source On-State Resistance ^a		V _{GS} = 10 V, I _D = 10 A		0.008			
	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 9 A	5.5			Ω	
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 10 A		50		S	
Dynamic ^b					1		
Input Capacitance	C _{iss}			800			
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		165		pF	
Reverse Transfer Capacitance	C _{rss}	50		73			
		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A		15	23	nC	
Total Gate Charge	Q_g			6.8	10.2		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 5 \text{ V}, I_{D} = 10 \text{ A}$		2.5			
Gate-Drain Charge	Q_{gd}			2.3			
Gate Resistance	R_g	f = 1 MHz	0.36	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			16	23	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		12	16		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		16	22		
Fall Time	t _f			10	18		
Turn-On Delay Time	t _{d(on)}			8	16		
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.4 Ω		10	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 9 \text{ A}, \ V_{GEN} = 10 \text{ V}, \ R_g = 1 \ \Omega$		16	22		
Fall Time	t _f			8	15		
Drain-Source Body Diode Characterist	ics			1	•		
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			10	A	
Pulse Diode Forward Current ^a	I _{SM}				50		
Body Diode Voltage	V_{SD}	I _S = 9 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			15	30	ns	
ody Diode Reverse Recovery Charge Q _{rr}		L 0 A dl/dt 400 A/ T 05 00		6	12	nC	
Reverse Recovery Fall Time	t _a	$I_F = 9 \text{ A}, dI/dt = 100 \text{ A/}\mu\text{s}, T_J = 25 °C$		8			
Reverse Recovery Rise Time	t _b			7	İ	ns	

Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





服务热线:400-655-8788

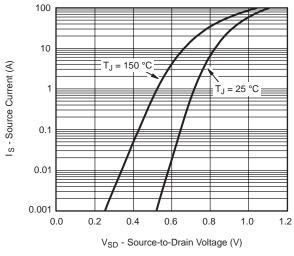
Q_q - Total Gate Charge (nC)

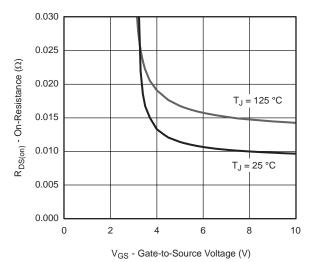
Gate Charge

T_J - Junction Temperature (°C)

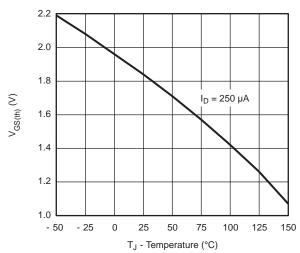
On-Resistance vs. Junction Temperature



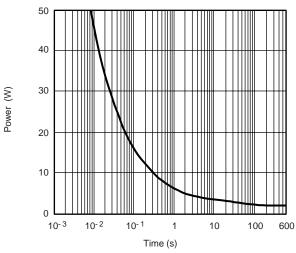




Source-Drain Diode Forward Voltage

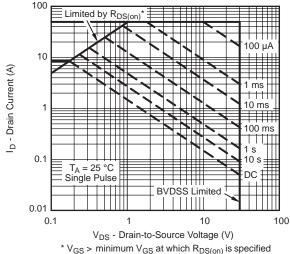


On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

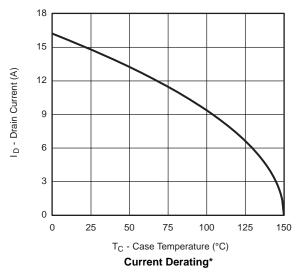


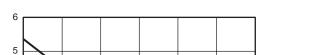


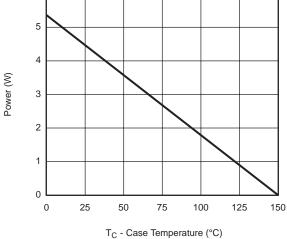
* $V_{GS} > \mbox{minimum } V_{GS}$ at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

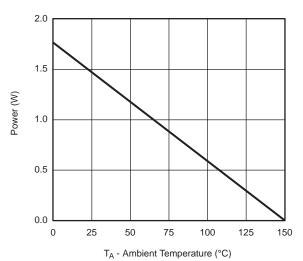








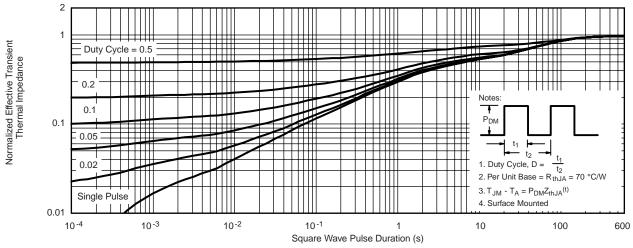
Power Derating, Junction-to-Foot



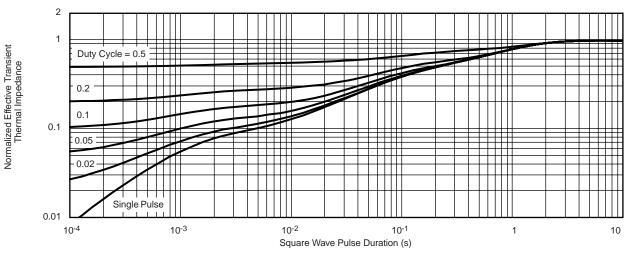
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



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